

**Notice of References Cited**

Application/Control No.

10/527,158

Applicant(s)/Patent Under  
Reexamination  
LUBITZ ET AL.

Examiner

Derek J. Rosenau

Art Unit

2834

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0127947	07-2003	Chandran et al.	310/328
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2000-012375	01-2000	Japan	Shimabara et al.	H01G04/30
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	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Machine translation of JP 2000-012375
	V	
	W	
	X	

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